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XP 956 – Effect of rev. Bt on heat flux profiles

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NSTX Results Review
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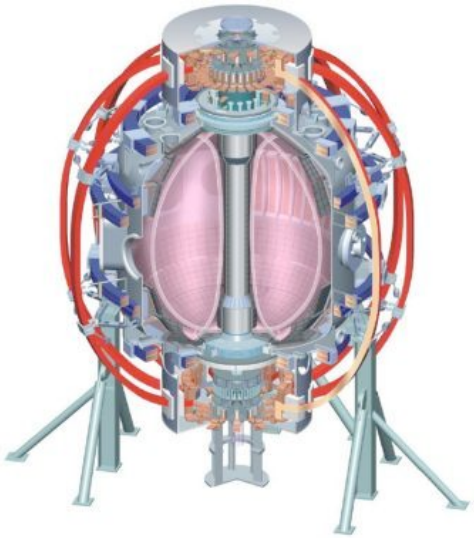

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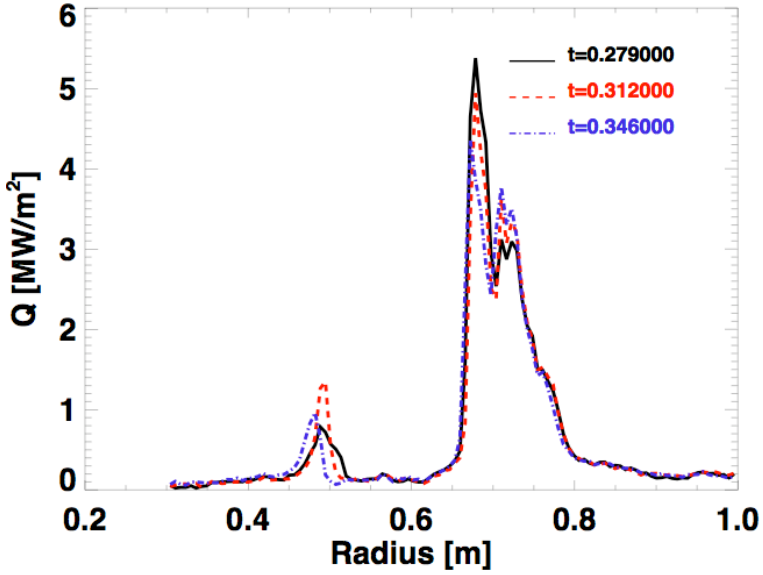
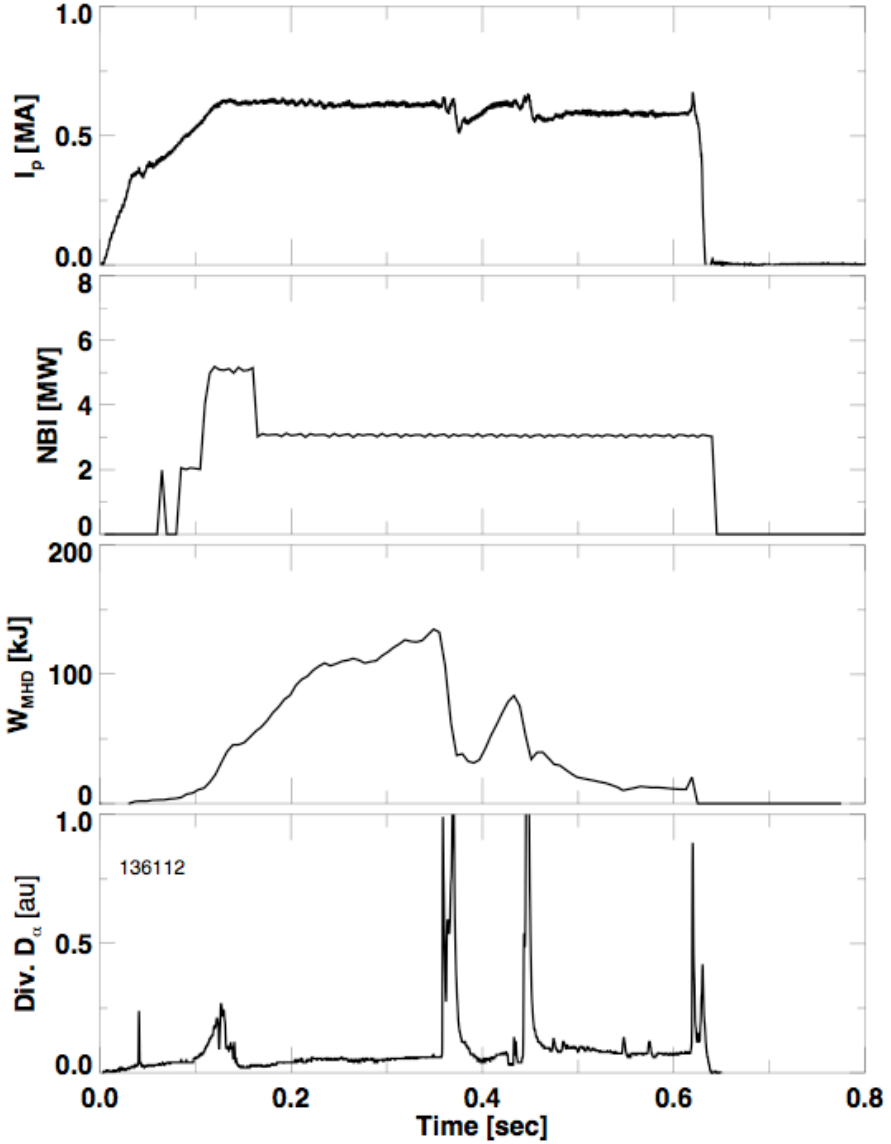
XP923: Edge T & T and in NSTX reversed B_t discharges

- Obtained I_p and P_{NBI} scan in reversed B_t discharges at low δ to characterize in /out heat flux profiles
  - Inner heat flux peaked; divertor attached
  - Needs SOLPS analysis





With normal B_t, q_{out} (q_{in}) profile is peaked (diffuse), indicating attachment (detachment)

- From XP 942: δ=0.4, (no pf1a used)